SCAS514C - JUNE 1995 - REVISED SEPTEMBER 1996

- **EPIC™** (Enhanced-Performance Implanted CMOS) 1-µm Process
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Flat (W), and DIP (J, N) Packages

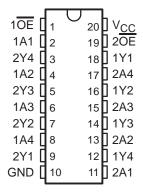
description

These octal buffers and line drivers are designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers transmitters.

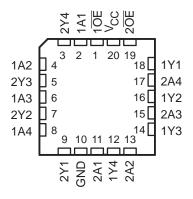
The 'AC244 are organized as two 4-bit buffers/drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes noninverted data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

The SN54AC244 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AC244 is characterized for operation from -40°C to 85°C.

SN54AC244 . . . J OR W PACKAGE SN74AC244 . . . DB. DW. N. OR PW PACKAGE (TOP VIEW)



SN54AC244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer)

INP	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z

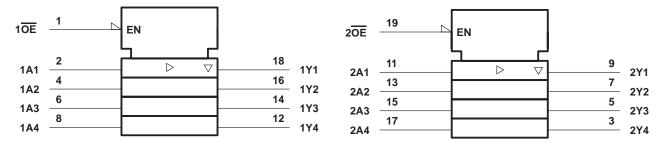


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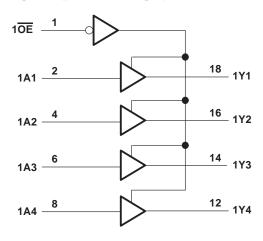


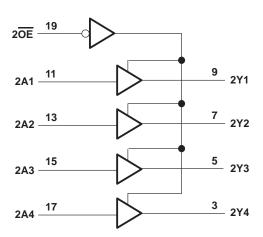
logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive Logic)





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

N packag	0.5 V to V _{CC} + 0.5 V 0.5 V to V _{CC} + 0.5 V ±20 mA ±20 mA ±50 mA ±200 mA ±200 mA ge0.6 W age1.6 W e1.3 W age0.7 W
Storage temperature range, 1stg	

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

recommended operating conditions (see Note 3)

			SN54A	SN54AC244		44 SN74AC244		
			MIN	MAX	MIN	MAX	UNIT	
Vсс	Supply voltage		2	6	2	6	V	
		V _{CC} = 3 V	2.1		2.1			
VIН	High-level input voltage	V _{CC} = 4.5 V	3.15		3.15		V	
		V _{CC} = 5.5 V	3.85		3.85			
		V _{CC} = 3 V		0.9		0.9		
VIL	Low-level input voltage	V _{CC} = 4.5 V		1.35		1.35	V	
		V _{CC} = 5.5 V		1.65		1.65		
٧ _I	Input voltage		0	VCC	0	VCC	V	
VO	Output voltage		0	Vcc	0	Vcc	V	
		V _{CC} = 3 V		-12		-12		
IOH	High-level output current	V _{CC} = 4.5 V		-24		-24	mA	
		V _{CC} = 5.5 V		-24		-24		
		V _{CC} = 3 V		12		12		
lOL	Low-level output current	V _{CC} = 4.5 V		24		24	mA	
		V _{CC} = 5.5 V		24		24		
Δt/Δν	Input transition rise or fall rate		0	8	0	8	ns/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

SN54AC244, SN74AC244 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCAS514C - JUNE 1995 - REVISED SEPTEMBER 1996

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DAMETED	TEST CONDITIONS	, I	T _A = 25°C			SN54AC244		SN74AC244		UNIT
PARAMETER		TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			3 V	2.9			2.9		2.9		
		I _{OH} = -50 μA	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4			
\ _{\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\}		I _{OH} = -12 mA	3 V	2.56			2.4		2.46		V
VOH			4.5 V	3.86			3.7		3.76		V
		I _{OL} = -24 mA	5.5 V	4.86			4.7		4.76		
		I _{OH} = -50 mA [†]	5.5 V				3.85				
		I _{OH} = -75 mA [†]	5.5 V						3.85		
			3 V			0.1		0.1		0.1	
		I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	
			5.5 V			0.1		0.1		0.1	
VOL	IOI = 12 mA 3 V 0.36 0.5	0.44									
VOL		I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	v
			5.5 V			0.36		0.5		0.44	
		$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	-	I _{OL} = 75 mA [†]	5.5 V							1.65	
1.	Data inputs	V _I = V _{CC} or GND	5.5 V			±0.1		±1		±1	μА
ll .	Control inputs	V _I = V _{CC} or GND	3.5 V			±0.1		±1		±1	μΑ
loz		$V_O = V_{CC}$ or GND, $V_{I(OE)} = V_{IL}$ or V_{IH}	5.5 V			±0.25		±5		±2.5	μА
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ
Ci		$V_I = V_{CC}$ or GND	5 V		2.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			SN54AC244		SN74AC244		UNIT	
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
t _{PLH}	А	Y	2	6.5	9	1	12.5	1.5	10	ns	
tpHL			2	6.5	9	1	12	2	10	115	
^t PZH	ŌĒ		V	2	6	10.5	1	11.5	1.5	11	20
t _{PZL}		ī	2.5	7.5	10	1	13	2	11	ns	
^t PHZ	ŌĒ	V	3	7	10	1	12.5	1.5	10.5	no	
tPLZ	OE	ī	2.5	7.5	10.5	1	13	2.5	11.5	ns	



SCAS514C - JUNE 1995 - REVISED SEPTEMBER 1996

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			SN54AC244		SN74AC244		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t _{PLH}	А	>	1.5	5	7	1	9.5	1	7.5	
^t PHL		T	1.5	5	7	1	9	1	7.5	ns
^t PZH	ŌĒ	V	1.5	5	7	1	9	1.5	8	no
t _{PZL}		Ĭ	1.5	5.5	8	1	10.5	1.5	8.5	ns
^t PHZ	ŌĒ	×	2.5	6.5	9	1	10.5	1	9.5	20
t _{PLZ}	OE .	r	2	6.5	9	1	11	2	9.5	ns

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CON	TYP	UNIT	
C _{pd}	Power dissipation capacitance per buffer/driver	$C_L = 50 pF$,	f = 1 MHz	45	pF

PARAMETER MEASUREMENT INFORMATION O 2×VCC **TEST** S1 500 Ω tPLH/tPHL Open From Output tPLZ/tPZL 2×V_{CC} **Under Test** tPHZ/tPZH Open C_L = 50 pF 500 Ω (see Note A) Output LOAD CIRCUIT **VCC** Control 50% V_{CC} 50% V_CC (low-level enabling) tPZL -VCC tPLZ -Input Output ≈ VCC 50% V_{CC} 50% V_{CC} Waveform 1 50% V_{CC} S1 at $2 \times V_{CC}$ ^tPLH (see Note B) tPHZ-^tPHL tPZH → Output ۷он Waveform 2 50% V_{CC} 50% V_{CC} 50% V_CC Output S1 at Open VOL (see Note B) **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS**

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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